Fletcher, William

From: F

Parker, Frederick

Sent:

Thursday, November 29, 2007 6:33 AM

To:

Fletcher, William

Subject: RE: 10/717,717

I have seen this stuff in color filter coating, it hard to find.

fred

From: Fletcher, William

Sent: Wednesday, November 28, 2007 5:15 PM

To: Meeks, Timothy; Parker, Frederick

Subject: 10/717,717

Gentlemen--

I have a case, 10/717,717, on which I would like your input.

I am having difficulty finding the claimed feature of applying a first alignment mark to a dummy substrate, followed by detection thereof, and application of a second alignment mark to a second dummy substrate, followed by detection thereof.

Any art that you know, suggestions, or different ways of looking at the claim would be appreciated!

Thanks.

William Fletcher
Primary Examiner
Division 1792

(571) 272-1419 william.fletcher@uspto.gov

Fletcher, William

From: Lin, James

Sent: Thursday, November 29, 2007 10:47 AM

To: Fletcher, William Subject: RE: 10/717,717

10699854 is from the same assignee and has similar claims, but not close enough for an ODP. '854 has the same concept of applying patterns onto a dummy substrate and detecting the patterns, but the background section taught this method so I just used that teaching as Applicant's admitted prior art. If I had to search for this concept, I would imagine that 118/663+ would be a good place to look.

Jimmy

From: Meeks, Timothy

Sent: Thursday, November 29, 2007 9:48 AM **To:** Fletcher, William; Parker, Frederick; Lin, James

Subject: RE: 10/717,717

Jimmy,

This case is similar to the one you brought by the other day (sealing an LCD substrate). Would you mind taking a look and letting Bill know of any art you may be aware of that may help him with this case?

Thanks, Tim

From: Fletcher, William

Sent: Wednesday, November 28, 2007 5:15 PM

To: Meeks, Timothy; Parker, Frederick

Subject: 10/717,717

Gentlemen--

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I am having difficulty finding the claimed feature of applying a first alignment mark to a dummy substrate, followed by detection thereof, and application of a second alignment mark to a second dummy substrate, followed by detection thereof.

Any art that you know, suggestions, or different ways of looking at the claim would be appreciated!

Thanks.

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